


<b>Search Notes</b>  	<b>Application/Control No.</b>  10673775	<b>Applicant(s)/Patent Under Reexamination</b>  MABUCHI, KEIJI
	<b>Examiner</b>  DENNIS HOGUE	<b>Art Unit</b>  2622

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
see attached EAST search history	2/25/2008	DH
see updated EAST search history	10/2/2008	DH
see updated EAST search history	3/6/2009	DH
348 / 220.1, 241, 294-324, 372 + keywords	2/25/2008	DH
257 / 223, 233 + keywords	10/2/2008	DH
250 / 208.1 + keywords	10/2/2008	DH
inventor search	10/2/2008	DH
update search	10/2/2008	DH
inventor search	3/6/2009	DH
update search	3/6/2009	DH
update search	11/2/2009	DH
inventor search	11/2/2009	DH
see updated EAST search history	11/2/2009	DH
consulted Tuan Ho and Nelson Hernandez regarding claim rejections	11/2/2009	DH
348 / 207.99 + keywords	4/30/2010	DH
257 / 225, 231, 292, 440, 443 + keywords	4/30/2010	DH
inventor search	4/30/2010	DH
update search	4/30/2010	DH
see updated EAST search history	4/30/2010	DH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
US-PGPUB, UPAD	(semiconductor same substrate same voltage same pixel same well).clm.	4/30/2010	DH
US-PGPUB, UPAD	(bias\$3 voltage same substrate same pixel same (readout or read\$3 out or transfer\$4)).clm.	4/30/2010	DH
US-PGPUB, UPAD	(bias\$3 same voltage same substrate same pixel near2 row).clm.	4/30/2010	DH

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